Main specifications

Mode l No.	NS8160MS	NS8080MS	NS8080SH	NS8040SH
Devices handled	QFP, TSOP, CSP, WLCSP, BGA, QFN, PLCC, LGA, PGA Min. 3 × 3 to Max. 50 × 50 (Lead pitch: 0.4 mm or more) ''			
Test mode	16-site (8 × 2)	-	-	-
	8-site (4 × 2)			-
	Square 4-site (2 × 2)			
	In-Line 4-site (4 × 1)			
	2-site Single			
	·			
Testing area	264 mm × 149 mm		184 mm × 149 mm	
	X: 30 Y: 60 (max X: 30 Y: 63.5)	X: 40 Y: 60 (max X: 60 Y: 63.5)	X: 40 Y: 60	X: 80 Y: 60
Heating method	Heating plate			
Index time	0.38 sec ~ (In-Line 4 up to 160 kgf) *2		0.39 sec ~ (In-Line 4 up to 120 kgf) *2	
	0.54 sec ~ (In-Line 4 up to 240 kgf) *2		_	
Maximum throughput (units per hour)	13,500 units (ambient temperature); 8,200 unit:		(high temperature)	10,000 units (ambient temperature) 6,100 units (high temperature)
Binning	Max. 6 bins (3 auto loaders, 3 manual loaders)			
Tray size	JEDEC (135.9 × 315.0) mm			
Max. contact pressure	240 kgf		120 kgf	
Temperature accuracy	+50°C to +90°C ±2°C '4 +90°C to +155°C ±3°C '4			+50°C to +90°C ±2°C +90°C to +130°C ±3°C
	Single-phase AC 200 to 240 V, 50/60Hz, 6 kVA			
Handler dimensions (mm)	1,850 (W) × 1,500 (D) × 1,970 (H) *3		1,850 (W) × 1,500 (D) × 1,850 (H) *3	
Weight	Approx. 1,090 kg		Approx. 1,000 kg	



• Please note that specifications and appearance of the product may change without notice for better performance

For orders or inquiries please contact us as shown below:

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IC Test Handler NS8000 series



^{*1:} Depends on socket size and socket pitch.
*2: Depends on the socket mounting height.
*3: Excluding handle, tower light, and LCD monitor.
*4: Contact us for temperature accuracy of NS80805H 8-site.

Compatibility of Socket Layout Kits

1. Socket Layout Kits (with heaten for NS8080HW can be used.

2. Socket Layout Kits for chamber type Handler can be used for Ambient mode test.